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| QUALIFICATION PLAN# 9290 |
| Test | Specification | Sample Size | Expected Completion Date |
| High Temperature Operating Life (HTOL)\* | JEDEC*JESD22-A108* | **1\*323\*451\*453\*77** | **PassPassPassPass** |
| Highly Accelerated Stress Test (HAST)\* | JEDEC *JESD22-A110* | **3\*773\*773\*773\*77** | **PassPassPassPass** |
| Early Life Failure (ELF) | MIL-STD-883 *Method 1015* | **3\*800** | **Pass** |
| High Temperature Storage Life (HTSL) | JEDEC *JESD22-A103* | **1\*322\*771\*771\*451\*771\*77** | **PassPassPassPassPassPass** |
| Latch-Up | JEDEC *JESD78* | **6** | **Pass 100mA** |
| Electrostatic Discharge*Human Body Model* | ESDA/JEDEC *JDS-001-2011* | **3/voltage** | **Pass 2500V** |
| Electrostatic Discharge*Field-Induced Charged Device Model* | JEDEC*JESD22-C101* | **3/voltage** | **Pass 750V** |

\*Preconditioned per JEDEC/IPC J-STD-020